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Stacked Annular Form Factor Film Capacitors for High Voltage and High Current Applications

Authors:

T.A. Hosking, SBE Inc.

M.A. Brubaker,
Consulting Engineer



Presented by:

Terry Hosking

V.P. Engineering

SBE Inc.

Power Ring Division



2005 PPPS Review



- 2005 Paper “*Annular Form Factor Film Capacitors*”
- Tests performed at 50KAmps & 130KAmps
- Low voltage testing for end connection integrity of Metallized Film capacitors
- March 2006 SBE issued patent for Pulse Film Technology, US Patent # 7,008,838

Annular Capacitor for Higher Voltage Applications



- Empirical determination that the voltage for single annular capacitor should be ~ 100 Volts/mm of capacitor thickness
- Higher voltage by series connection
- Simplest way is to stack them like pancakes
- Connection without terminals is simplest and most space efficient
 - Fixed or pressure connections possible

Stacking Annular Capacitors for High Voltage



- Consider the case for pressure connections
 - Interconnect accomplished with knitted wire mesh “gasket”
- Possible advantages of a “stacked” metallized film capacitor configuration
 - Higher energy density than foil designs
 - Lighter weight than conventional oil impregnated designs
 - Low cost opportunity due to terminal simplicity



Advantages



- Modularity
- Common capacitor building block
- Capacitance/voltage tailored to application by adjusting number of blocks used
- Capacitor blocks separately replaceable



Advantages (cont'd)



- Stacked coaxial geometry allows for low ESL
- Round capacitor reduces radial voltage gradient
- Uniform axial voltage grading
- Consider an 8 series-section capacitor

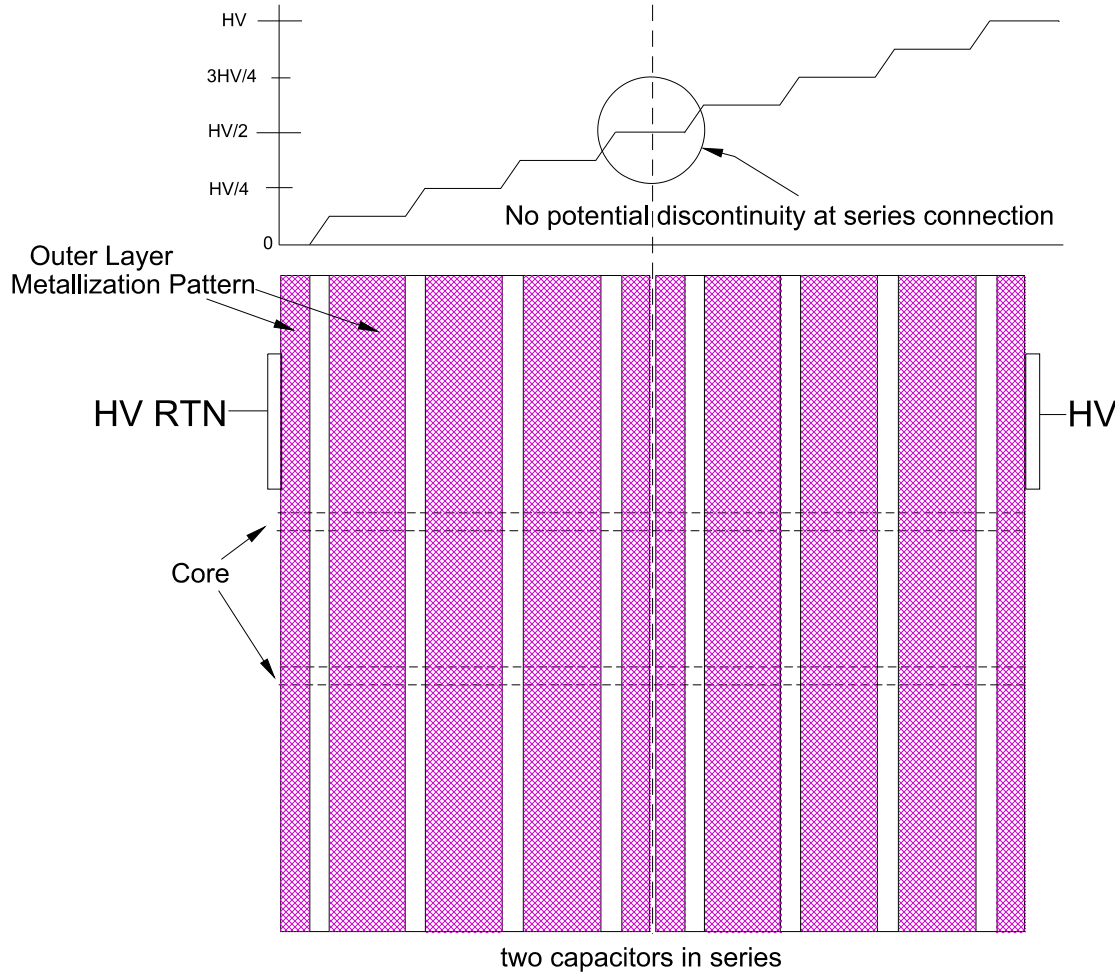


Series-Section Capacitor Design



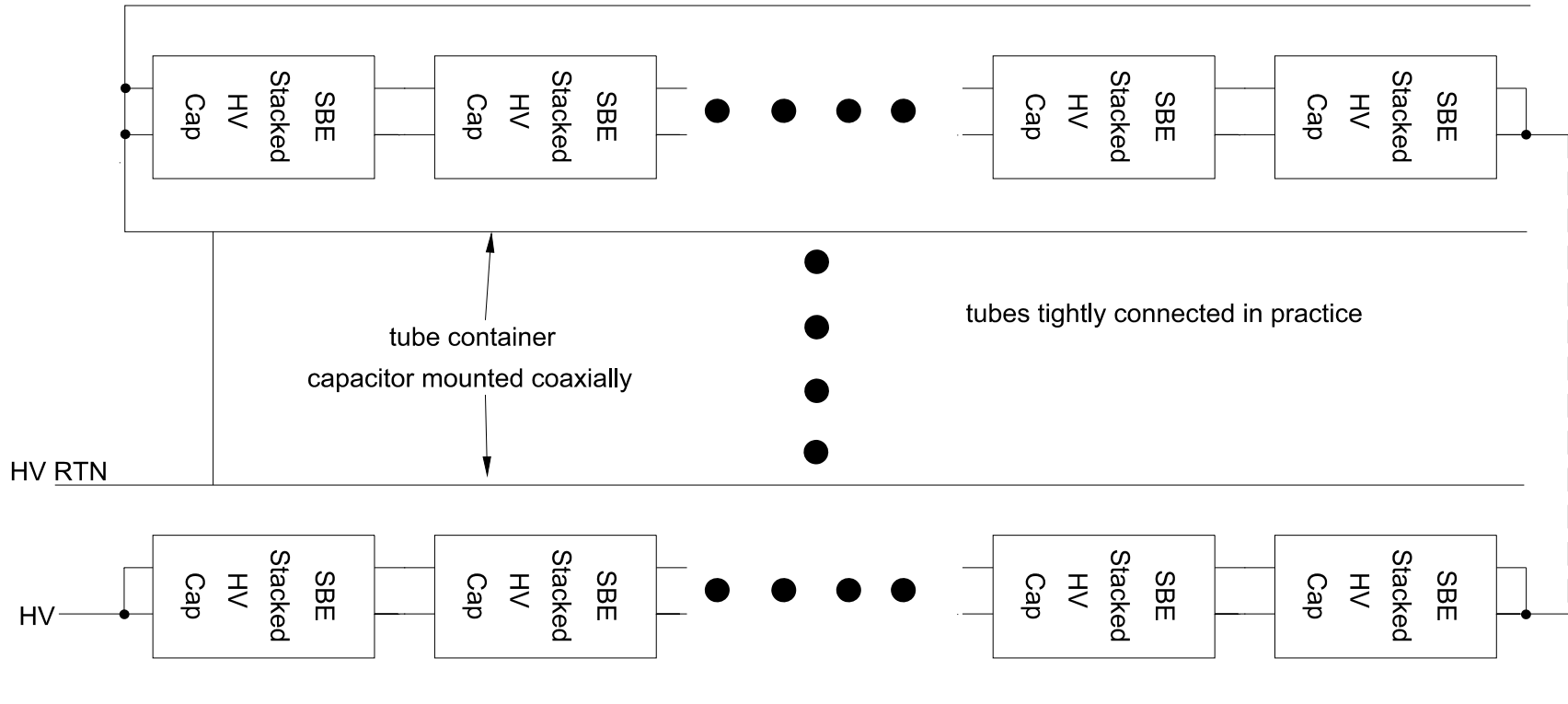
UNIFORM AXIAL VOLTAGE GRADING

Each capacitor is an 8 section series design





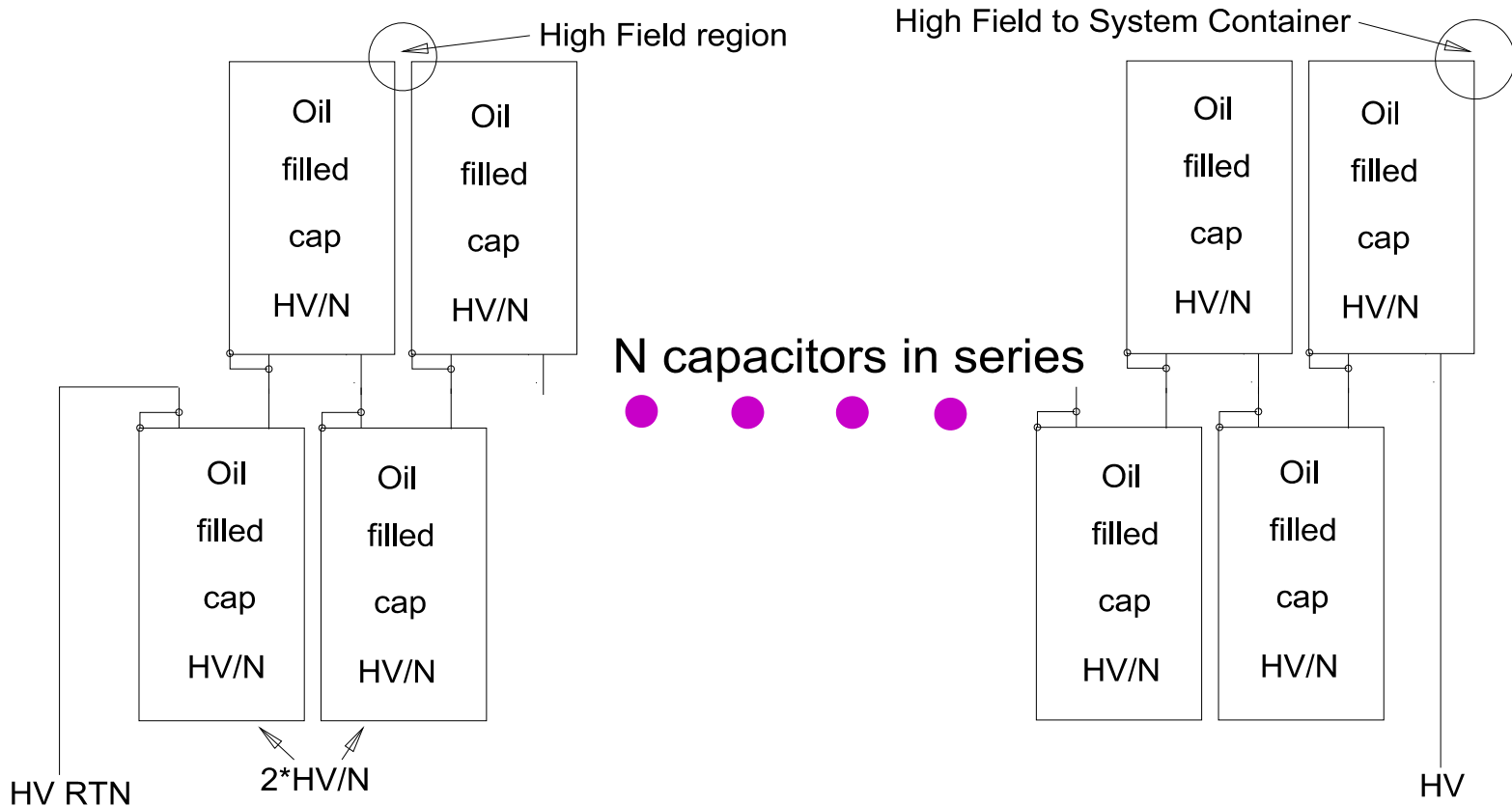
Advantages of Stacking Annular Capacitors



- Uniform axial voltage grading along the stack
- Round geometry reduces radial potential gradient
- Coaxial geometry reduces ESL



Traditional Series Connection



- Schematic showing series string of traditional “oil-filled” caps
- Arranged to minimize ESL



Testing



- Test Conditions
 - Large Voltage Swings and Peak Currents
 - Extreme, and Multiple, Reversals
- Examination of the use of knitted wire mesh for interconnection

Capacitor Design



- Two of the following units were used in building the High Voltage stack

8 series-section, Metallized Polypropylene film design

Wound on hollow phenolic core with 1.5"/38mm I.D.

7.5 μ F, \pm 10%

8 KVDC rating

5.6"/142mm O.D

3.0"/76mm Axial Length

- Resulting stack

3.75 μ F rated at 16 KVDC



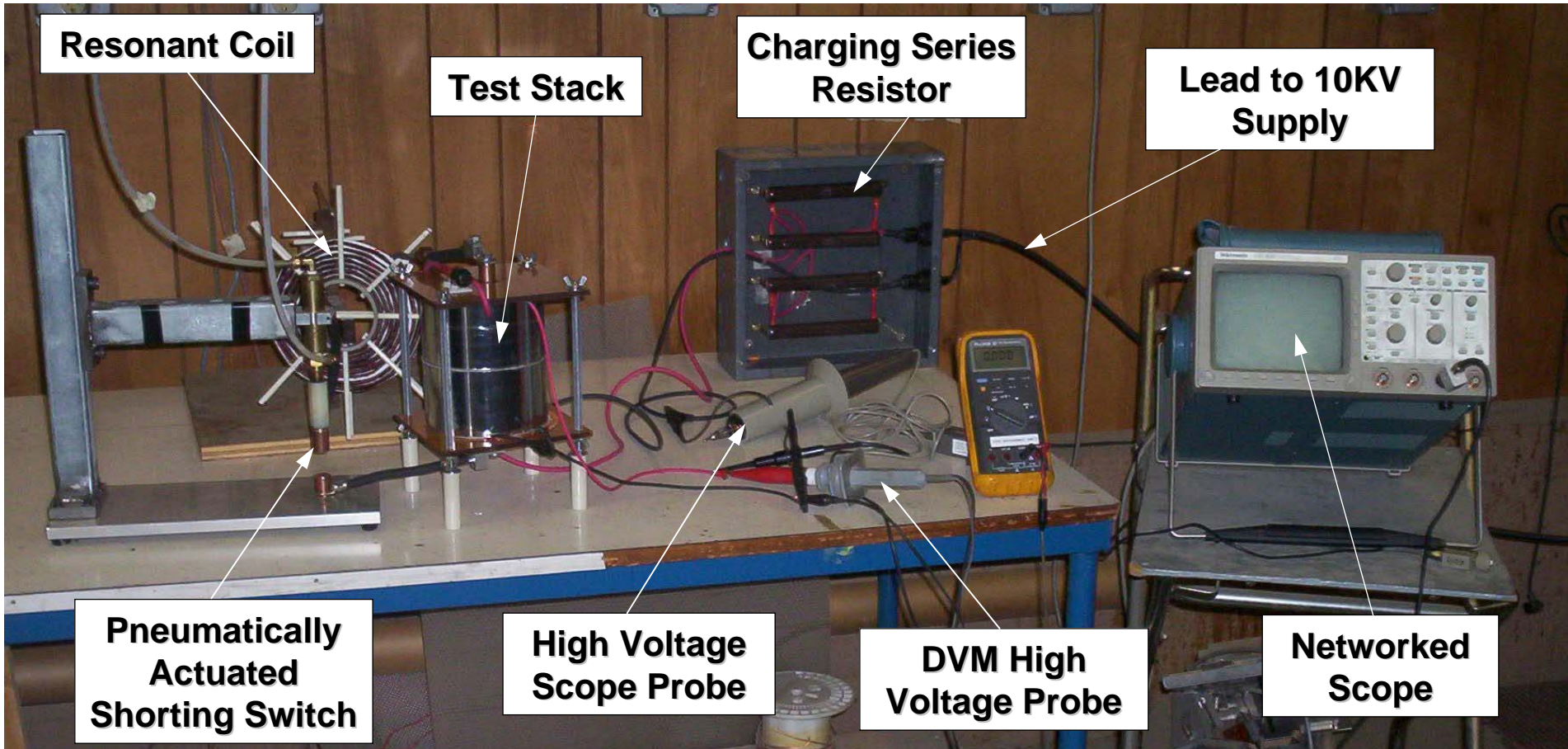
Interconnect



- Tecknit knitted wire mesh used between the 2 capacitor stacked sections, and on each end face of the stack to contact to copper terminal plates
 - Tecknit part # 23-502
 - Tin coated copper-clad steel (0.0045"):
 - ⇒ Steel core, 57% by weight
 - ⇒ Copper cladding, 40% by weight
 - ⇒ Tin coating, 3% by weight



Test Setup



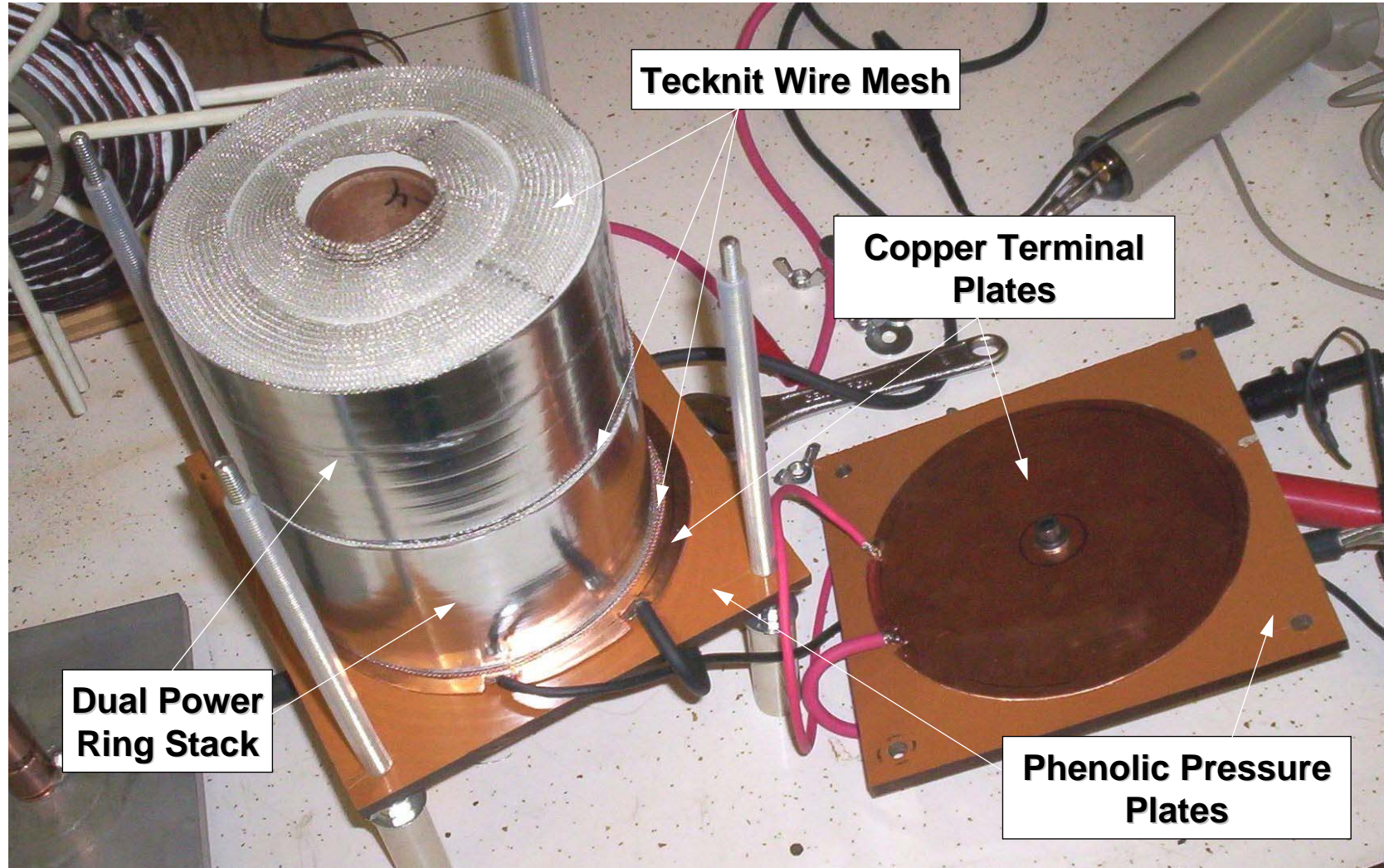


Assembled Test Stack in Fixture



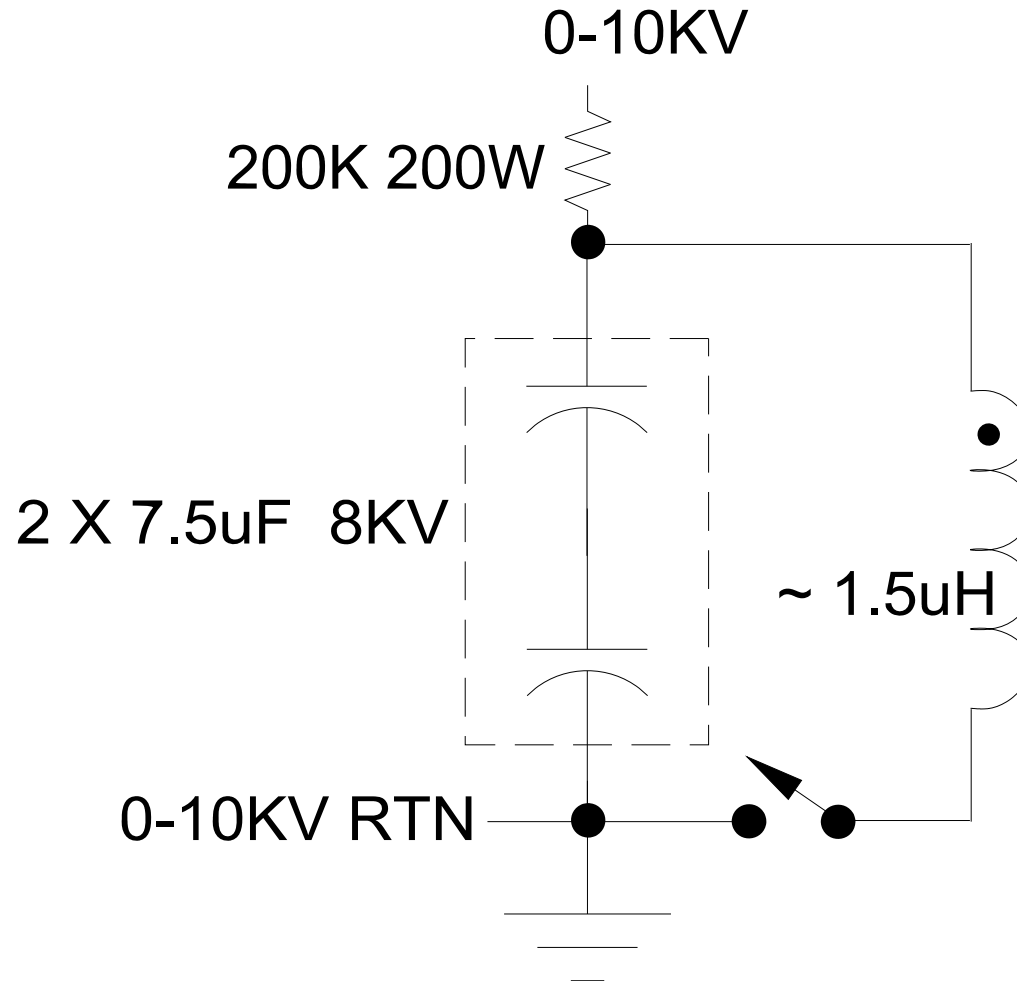


Test Stack





Test Schematic

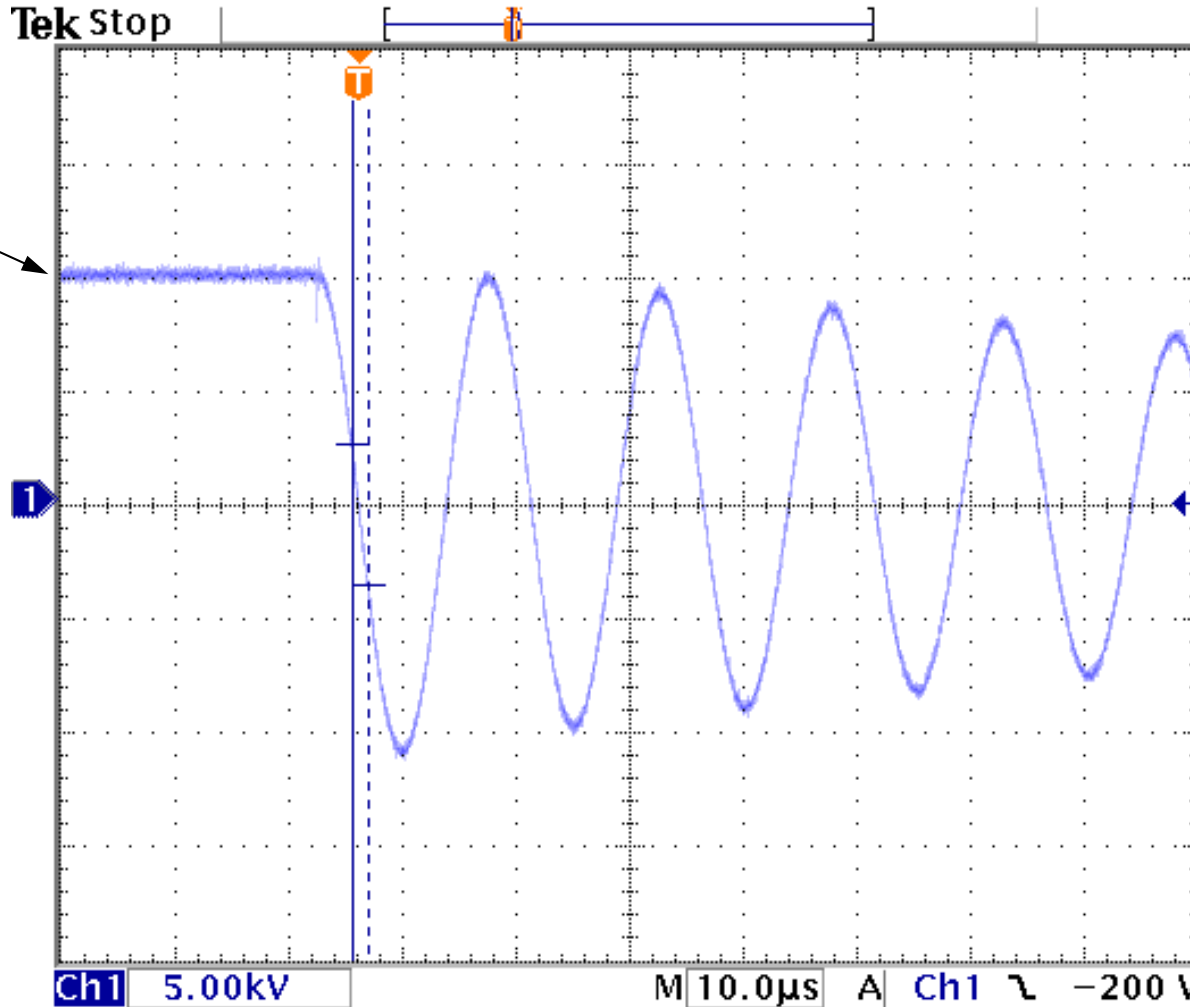




Test Waveform



10KV



Δ: 6.20kV
@: 2.40kV
Δ: 1.40µs
@: -600ns

1 26.20 %

20 May 2007
15:35:20

Test Waveform Description



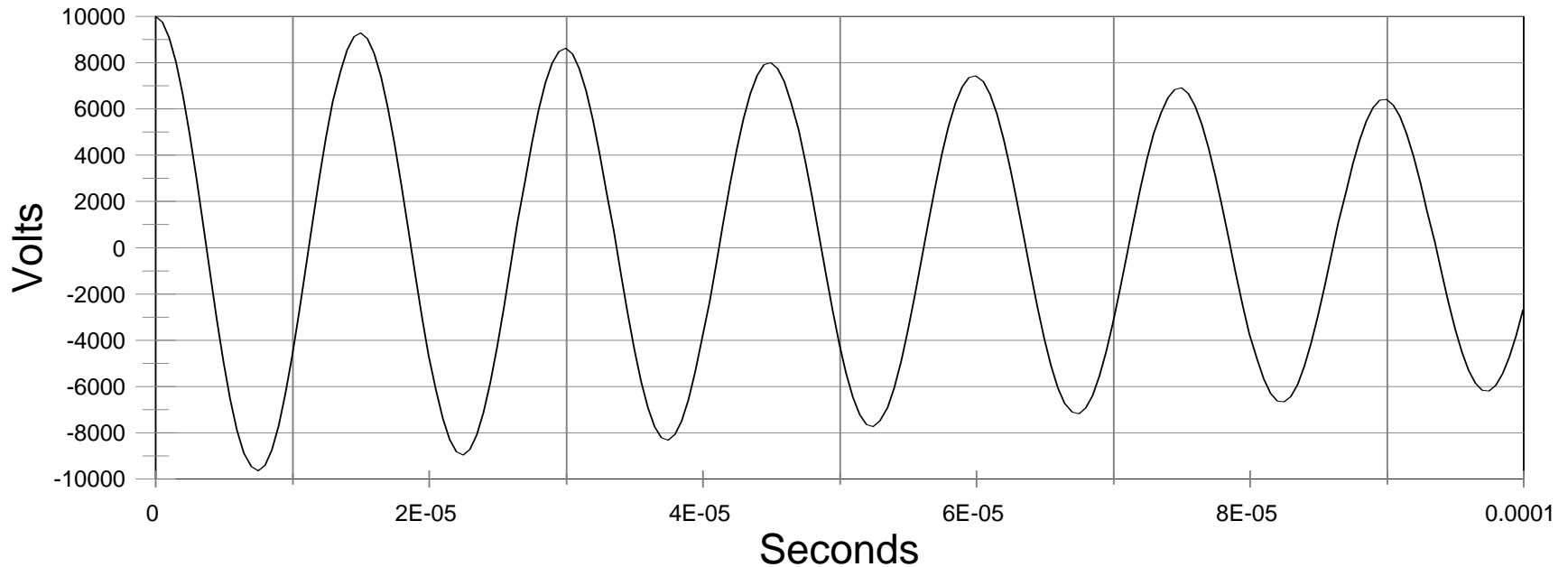
- Every discharge results in multiple high current pulses, not just one as for typical applications
- Multiple, severe reversals
- All transitions >12 KV Peak-to-Peak result in corona damage
- Waveform indicating more than 100% reversal is an artifact of the High Voltage probe's frequency response



Theoretical Waveform



**Calculated Response
of test system when discharged**



R = 15 milliohms, L = 1.53 μ H, C = 3.71 μ F
Calculation time step = 500 nanoseconds

Test Procedure, Results & Observations



- Two capacitor stacks were assembled (Stack 1, Stack 2)
- 3 total tests were conducted
- Test 1, Stack 1
- Charge to 10KV
- After 3,000 discharges at 16.6KAmps
 - Cap loss less than 2%, initial cap 3.715 μ F
 - Gasket weakly welded to end spray surface in multiple locations

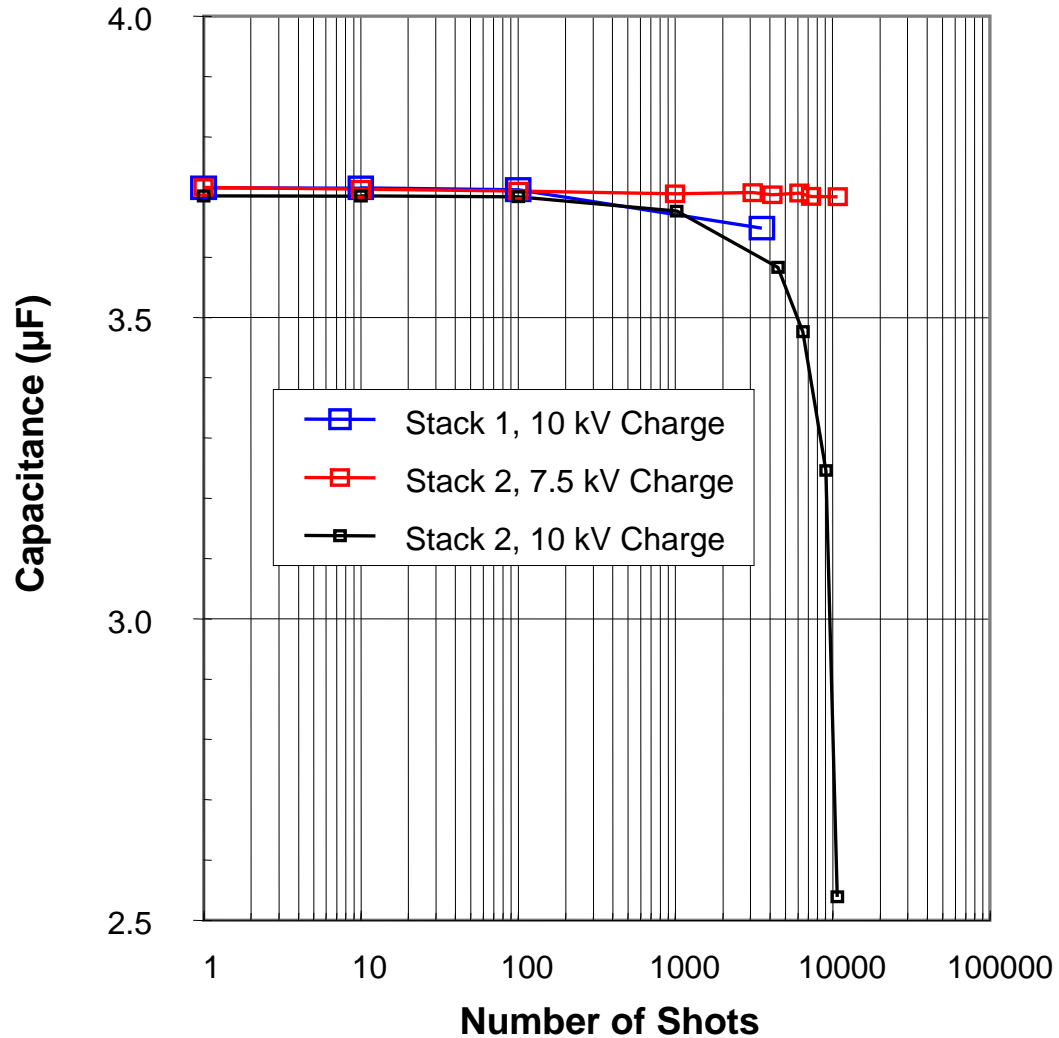
Test Procedure, Results & Observations



- Test 2: Stack 2 charged to 7.5KV, after 10,000 discharges at 12.2KAmps
 - Cap loss less than 1%, initial cap 3.70 μ F
 - No visible mechanical issues
- Test 3: Stack 2 charged to 10KV, after an additional 10,000 discharges at 16.6KAmps
 - Cap loss of 46% observed after the total of 20,000 discharges
 - Severe degradation of the end spray was apparent on the top capacitor section
 - An additional 3,000 discharges led to the failure of the top capacitor element in the stack



Capacitor Test Results



Interconnect Test



- Determine pressure on Tecknit as used in the capacitor test
 - Measure height of top plate of assembled fixture as tested
 - Release fixture pressure, add weight on top plate to duplicate same height of assembly
 - Figure the force per unit area on mesh
- Separate crush test performed to determine thickness vs. pressure behavior of a single layer of knitted wire mesh
 - 2" x 2" steel plates to sandwich Tecknit mesh
 - Plot thickness vs. pressure as force increases



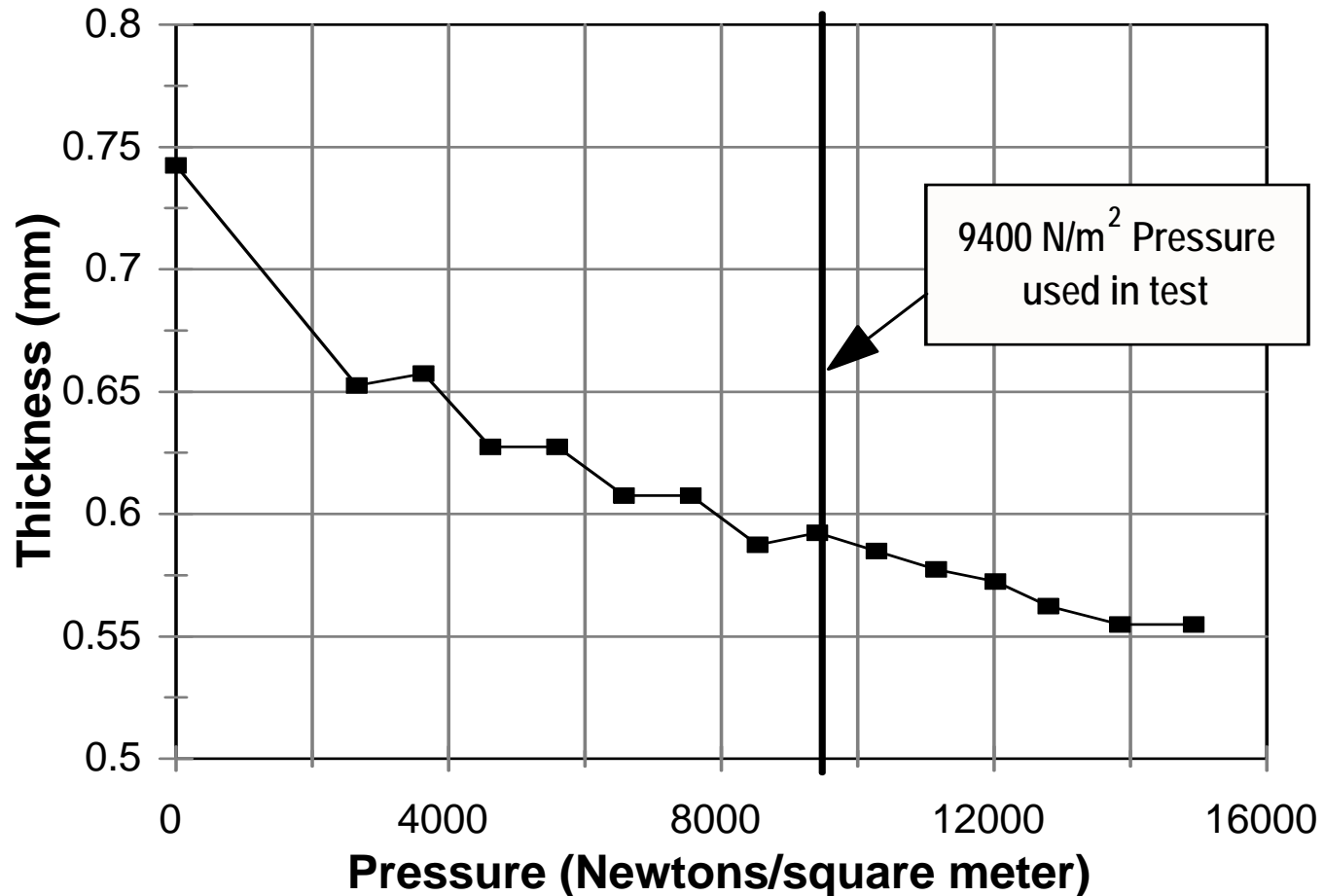


Interconnect Test Results

Force vs. Crush



Tecknit 23-502 Thickness vs. Pressure





Interconnect Implications



- Compliance of mesh
 - Mesh made in tubular shape, then crushed flat
 - Easy to crush to about 4x the wire thickness
 - Each layer has about 0.29mm compliance
- Effect on stack
 - Non-uniform pressure results in smaller contact areas
 - Need a more rigid plate to distribute pressure
 - Capacitor end spray surface flatness is important
 - Capacitor could withstand 5x more force than was used during the test if spread uniformly across the capacitor conducting surfaces



Summary



- Brutal test, designed to determine failure modes
 - No energy transfer from cap to a “load” for this test
 - No-one would use the capacitor in this manner
- Graceful failure mode, gradual capacitance loss
- Offers perfectly symmetric voltage grading at the system level
- Ability to replace a single capacitor element, rather than an entire assembly



Conclusion



- The modular coaxial stacked concept may offer advantages for pulse power applications
- Preliminary test results are very encouraging
- Future work to be done regarding the interconnect system



Thank you!



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